

**Notice of References Cited**

Application/Control No.

10/016,448

Applicant(s)/Patent Under
Reexamination
BAILIS ET AL.

Examiner

Cynthia Britt

Art Unit

2133

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,844,917	12-1998	Salem et al.	714/724
	B	US-6,012,148	01-2000	Laberge et al.	714/2
	C	US-			
	D	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Boundary Scan Access of Built-in Self-test for Field Programmable Gate Arrays" by Gibson et al. Tenth Annual IEEE International Proceedings ASIC Conference and Exhibit Publication Date: 7-10 Sept. 1997, pages 57 – 61, Inspec Accession Number: 5774208
	V	"pFSB Technology Enables Field Programmability in an ASIC Environment" by Coli et al. in Digest of Papers Compcon Spring '93, Publication Date: 22-26 Feb. 1993, pages: 385 - 389 Inspec Accession Number: 4750288
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.